

PROCEEDINGS OF SPIE

# ***Anomaly Detection and Imaging with X-Rays (ADIX) VIII***

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**3–4 May 2023**  
**Orlando, Florida, United States**

*Sponsored and Published by*  
SPIE

**Volume 12531**

Proceedings of SPIE 0277-786X, V. 12531

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Please use the following format to cite material from these proceedings:

Author(s), "Title of Paper," in *Anomaly Detection and Imaging with X-Rays (ADIX) VIII*, edited by Amit Ashok, Joel A. Greenberg, Michael E. Gehm, Proc. of SPIE 12531, Seven-digit Article CID Number (DD/MM/YYYY); (DOI URL).

ISSN: 0277-786X

ISSN: 1996-756X (electronic)

ISBN: 9781510661769

ISBN: 9781510661776 (electronic)

Published by

**SPIE**

P.O. Box 10, Bellingham, Washington 98227-0010 USA

Telephone +1 360 676 3290 (Pacific Time)

[SPIE.org](http://SPIE.org)

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